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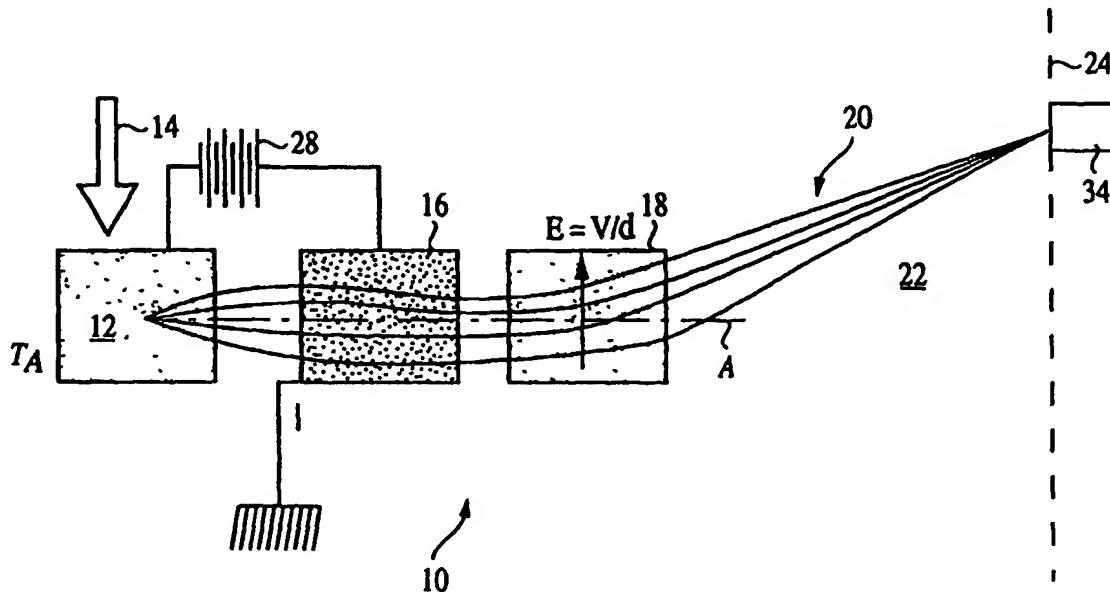
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(54) Title: SPECTROGRAPH TIME OF FLIGHT SYSTEM FOR LOW ENERGY NEUTRAL PARTICLES



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(57) Abstract: A mass spectrometer is provided for identifying mass and velocity distributions in a continuous ion beam is configured with a circular dispersive system creating a rotating electromagnetic field, which is capable of deflecting the ion beam from an initial direction, and a circular position-sensitive detector intercepting the deflected ion beam and providing information from which the ion mass-per-charge ratio is determined